

4-15-04

FORM PTO-1449	ATTY. DKT NO. 01-617	SER. NO. 101824497
	APPLICANT Endou, et al.	
	FILING DATE April 15, 2004	GROUP

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

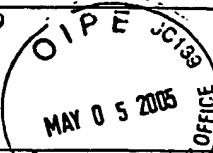
TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
									Eng. Abstract
<i>JP</i>	JP-A-10-125620 (discussed on page 2 of the specification)	05/15/98	JAPAN						X
<i>JP</i>	JP-A-2000-12846 (discussed on page 2 of the specification)	01/14/00	JAPAN						X

* Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER <i>Phil Pius</i>	DATE CONSIDERED <i>8/6/05</i>
---------------------------	-------------------------------

FORM PTO-1449		ATTY. DKT NO. 01-617	SER. NO. 10/824,497
		APPLICANT ENDOU et al.	
		FILING DATE April 15, 2004	GROUP 2812

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

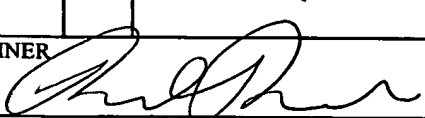
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

									TRANSLATION	
		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
									Eng. Abstract	
BP		WO 01/84609	11/8/01	PCT						

* Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
	8/6/05